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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Active
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	24MHz
Connectivity	I <sup>2</sup> C, IrDA, LINbus, SPI, UART/USART
Peripherals	DMA, PDR, POR, PVD, PWM, Temp Sensor, WDT
Number of I/O	112
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 16x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-LQFP (20x20)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f100zet6b">https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f100zet6b</a>

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# 1 Introduction

This datasheet provides the ordering information and mechanical device characteristics of the STM32F100xC, STM32F100xD and STM32F100xE value line microcontrollers. In the rest of the document, the STM32F100xC, STM32F100xD and STM32F100xE are referred to as high-density value line devices.

This STM32F100xC, STM32F100xD and STM32F100xE datasheet should be read in conjunction with the STM32F100xx high-density ARM®-based 32-bit MCUs *reference manual (RM0059)*. For information on programming, erasing and protection of the internal Flash memory please refer to the *STM32F100xx high-density value line Flash programming manual (PM0072)*. The reference and Flash programming manuals are both available from the STMicroelectronics website [www.st.com](http://www.st.com).

For information on the Cortex®-M3 core please refer to the Cortex®-M3 Technical Reference Manual, available from the <http://infocenter.arm.com>.



## 2 Description

The STM32F100xx value line family incorporates the high-performance ARM® Cortex®-M3 32-bit RISC core operating at a 24 MHz frequency, high-speed embedded memories (Flash memory up to 512 Kbytes and SRAM up to 32 Kbytes), a flexible static memory control (FSMC) interface (for devices offered in packages of 100 pins and more) and an extensive range of enhanced peripherals and I/Os connected to two APB buses. All devices offer standard communication interfaces (up to two I<sup>2</sup>Cs, three SPIs, one HDMI CEC, up to three USARTs and 2 UARTS), one 12-bit ADC, two 12-bit DACs, up to 9 general-purpose 16-bit timers and an advanced-control PWM timer.

The STM32F100xx high-density value line family operates in the –40 to +85 °C and –40 to +105 °C temperature ranges, from a 2.0 to 3.6 V power supply. A comprehensive set of power-saving mode allows the design of low-power applications.

The STM32F100xx value line family includes devices in three different packages ranging from 64 pins to 144 pins. Depending on the device chosen, different sets of peripherals are included, the description below gives an overview of the complete range of peripherals proposed in this family.

These features make the STM32F100xx value line microcontroller family suitable for a wide range of applications such as motor drives, application control, medical and handheld equipment, PC and gaming peripherals, GPS platforms, industrial applications, PLCs, inverters, printers, scanners, alarm systems, video intercoms, and HVACs.

## 2.2 Overview

### 2.2.1 ARM® Cortex®-M3 core with embedded Flash and SRAM

The ARM Cortex®-M3 processor is the latest generation of ARM processors for embedded systems. It has been developed to provide a low-cost platform that meets the needs of MCU implementation, with a reduced pin count and low-power consumption, while delivering outstanding computational performance and an advanced system response to interrupts.

The ARM Cortex®-M3 32-bit RISC processor features exceptional code-efficiency, delivering the high-performance expected from an ARM core in the memory size usually associated with 8- and 16-bit devices.

The STM32F100xx value line family having an embedded ARM core, is therefore compatible with all ARM tools and software.

### 2.2.2 Embedded Flash memory

Up to 512 Kbytes of embedded Flash memory is available for storing programs and data.

### 2.2.3 CRC (cyclic redundancy check) calculation unit

The CRC (cyclic redundancy check) calculation unit is used to get a CRC code from a 32-bit data word and a fixed generator polynomial.

Among other applications, CRC-based techniques are used to verify data transmission or storage integrity. In the scope of the EN/IEC 60335-1 standard, they offer a means of verifying the Flash memory integrity. The CRC calculation unit helps compute a signature of the software during runtime, to be compared with a reference signature generated at link-time and stored at a given memory location.

### 2.2.4 Embedded SRAM

Up to 32 Kbytes of embedded SRAM accessed (read/write) at CPU clock speed with 0 wait states.

### 2.2.5 FSMC (flexible static memory controller)

The FSMC is embedded in the high-density value line family. It has four Chip Select outputs supporting the following modes: SRAM, PSRAM, and NOR.

Functionality overview:

- The three FSMC interrupt lines are ORed in order to be connected to the NVIC
- No read FIFO
- Code execution from external memory
- No boot capability
- The targeted frequency is HCLK/2, so external access is at 12 MHz when HCLK is at 24 MHz

### 2.2.6 LCD parallel interface

The FSMC can be configured to interface seamlessly with most graphic LCD controllers. It supports the Intel 8080 and Motorola 6800 modes, and is flexible enough to adapt to

**TIM2, TIM3, TIM4, TIM5**

STM32F100xx devices feature four synchronizable 4-channel general-purpose timers. These timers are based on a 16-bit auto-reload up/downcounter and a 16-bit prescaler. They feature 4 independent channels each for input capture/output compare, PWM or one-pulse mode output. This gives up to 12 input captures/output compares/PWMs on the largest packages.

The TIM2, TIM3, TIM4, TIM5 general-purpose timers can work together or with the TIM1 advanced-control timer via the Timer Link feature for synchronization or event chaining.

TIM2, TIM3, TIM4, TIM5 all have independent DMA request generation.

These timers are capable of handling quadrature (incremental) encoder signals and the digital outputs from 1 to 3 hall-effect sensors.

Their counters can be frozen in debug mode.

**TIM12, TIM13 and TIM14**

These timers are based on a 16-bit auto-reload upcounter and a 16-bit prescaler.

TIM12 has two independent channels, whereas TIM13 and TIM14 feature one single channel for input capture/output compare, PWM or one-pulse mode output.

Their counters can be frozen in debug mode.

**TIM15, TIM16 and TIM17**

These timers are based on a 16-bit auto-reload upcounter and a 16-bit prescaler.

TIM15 has two independent channels, whereas TIM16 and TIM17 feature one single channel for input capture/output compare, PWM or one-pulse mode output.

The TIM15, TIM16 and TIM17 timers can work together, and TIM15 can also operate with TIM1 via the Timer Link feature for synchronization or event chaining.

TIM15 can be synchronized with TIM16 and TIM17.

TIM15, TIM16, and TIM17 have a complementary output with dead-time generation and independent DMA request generation

Their counters can be frozen in debug mode.

**Basic timers TIM6 and TIM7**

These timers are mainly used for DAC trigger generation. They can also be used as a generic 16-bit time base.

**Independent watchdog**

The independent watchdog is based on a 12-bit downcounter and 8-bit prescaler. It is clocked from an independent 40 kHz internal RC and as it operates independently from the main clock, it can operate in Stop and Standby modes. It can be used as a watchdog to reset the device when a problem occurs, or as a free running timer for application timeout management. It is hardware or software configurable through the option bytes. The counter can be frozen in debug mode.

**Window watchdog**

The window watchdog is based on a 7-bit downcounter that can be set as free running. It can be used as a watchdog to reset the device when a problem occurs. It is clocked from the main clock. It has an early warning interrupt capability and the counter can be frozen in debug mode.

**SysTick timer**

This timer is dedicated for OS, but could also be used as a standard down counter. It features:

- A 24-bit down counter
- Autoreload capability
- Maskable system interrupt generation when the counter reaches 0.
- Programmable clock source

**2.2.18 I<sup>2</sup>C bus**

The I<sup>2</sup>C bus interface can operate in multimaster and slave modes. It can support standard and fast modes.

It supports dual slave addressing (7-bit only) and both 7/10-bit addressing in master mode. A hardware CRC generation/verification is embedded.

The interface can be served by DMA and it supports SM Bus 2.0/PM Bus.

**2.2.19 Universal synchronous/asynchronous receiver transmitter (USART)**

The STM32F100xx value line embeds three universal synchronous/asynchronous receiver transmitters (USART1, USART2 and USART3).

The available USART interfaces communicate at up to 3 Mbit/s. They provide hardware management of the CTS and RTS signals, they support IrDA SIR ENDEC, the multiprocessor communication mode, the single-wire half-duplex communication mode and have LIN Master/Slave capability.

The USART interfaces can be served by the DMA controller.

**2.2.20 Universal asynchronous receiver transmitter (UART)**

The STM32F100xx value line embeds 2 universal asynchronous receiver transmitters (UART4, and UART5).

The available UART interfaces support IrDA SIR ENDEC, the multiprocessor communication mode, the single-wire half-duplex communication mode and have LIN Master/Slave capability.

The UART interfaces can be served by the DMA controller.

**2.2.21 Serial peripheral interface (SPI)**

Up to three SPIs are able to communicate up to 12 Mbit/s in slave and master modes in full-duplex and simplex communication modes. The 3-bit prescaler gives 8 master mode frequencies and the frame is configurable to 8 bits or 16 bits.

The SPIs can be served by the DMA controller.



Table 5. FSMC pin definition (continued)

Pins	FSMC		LQFP100 <sup>(1)</sup>
	NOR/PSRAM/SRAM	NOR/PSRAM Mux	
PG0	A10	-	-
PG1	A11	-	-
PE7	D4	DA4	Yes
PE8	D5	DA5	Yes
PE9	D6	DA6	Yes
PE10	D7	DA7	Yes
PE11	D8	DA8	Yes
PE12	D9	DA9	Yes
PE13	D10	DA10	Yes
PE14	D11	DA11	Yes
PE15	D12	DA12	Yes
PD8	D13	DA13	Yes
PD9	D14	DA14	Yes
PD10	D15	DA15	Yes
PD11	A16	A16	Yes
PD12	A17	A17	Yes
PD13	A18	A18	Yes
PD14	D0	DA0	Yes
PD15	D1	DA1	Yes
PG2	A12	-	-
PG3	A13	-	-
PG4	A14	-	-
PG5	A15	-	-
PG6	-	-	-
PG7	-	-	-
PD0	D2	DA2	Yes
PD1	D3	DA3	Yes
PD3	CLK	CLK	Yes
PD4	NOE	NOE	Yes
PD5	NWE	NWE	Yes
PD6	NWAIT	NWAIT	Yes
PD7	NE1	NE1	Yes
PG9	NE2	NE2	-

Table 15. STM32F100xxB maximum current consumption in Sleep mode, code running from Flash or RAM

Symbol	Parameter	Conditions	f <sub>HCLK</sub>	Max <sup>(1)</sup>		Unit
				T <sub>A</sub> = 85 °C	T <sub>A</sub> = 105 °C	
I <sub>DD</sub>	Supply current in Sleep mode	External clock <sup>(2)</sup> all peripherals enabled	24 MHz	14.1	14.3	mA
			16 MHz	9.7	10.3	
			8 MHz	5.9	6.2	
		External clock <sup>(2)</sup> , all peripherals disabled	24 MHz	4.2	4.6	
			16 MHz	3.7	4.1	
			8 MHz	2.9	3.4	
		HSI clock <sup>(2)</sup> , all peripherals enabled	24 MHz	12.5	12.7	
			16 MHz	8.2	8.5	
			8 MHz	6.4	6.6	
		HSI clock <sup>(2)</sup> , all peripherals disabled	24 MHz	2.3	2.5	
			16 MHz	1.7	2	
			8 MHz	1.4	1.7	

1. Based on characterization, tested in production at V<sub>DD</sub> max and f<sub>HCLK</sub> max with peripherals enabled.

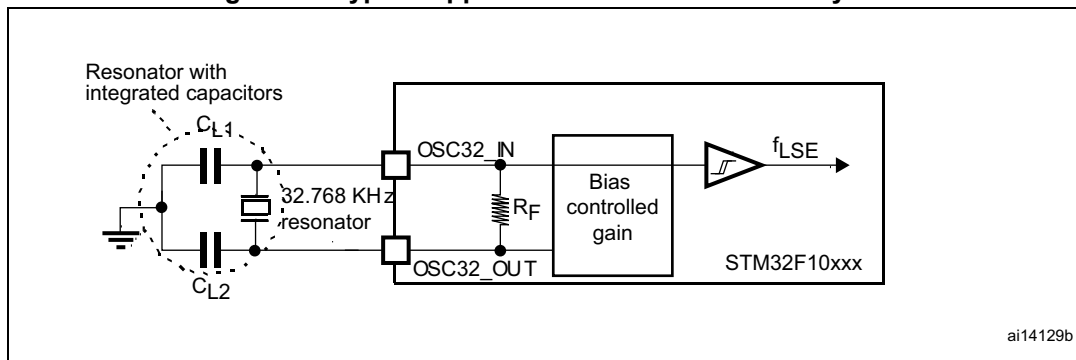
2. External clock or HSI frequency is 8 MHz and PLL is on when f<sub>HCLK</sub> > 8 MHz.

Table 17. Typical current consumption in Run mode, code with data processing running from Flash

Symbol	Parameter	Conditions	f <sub>HCLK</sub>	Typical values <sup>(1)</sup>		Unit
				All peripherals enabled <sup>(2)</sup>	All peripherals disabled	
I <sub>DD</sub>	Supply current in Run mode	Running on high-speed external clock with an 8 MHz crystal <sup>(3)</sup>	24 MHz	14.1	9.5	mA
			16 MHz	10	6.85	
			8 MHz	5.8	4.05	
			4 MHz	3.6	2.65	
			2 MHz	2.3	1.85	
			1 MHz	1.7	1.46	
			500 kHz	1.4	1.3	
			125 kHz	1.15	1.1	
		Running on high-speed internal RC (HSI)	24 MHz	13.4	8.7	
			16 MHz	9.3	6.2	
			8 MHz	5.2	3.45	
			4 MHz	2.95	2.1	
			2 MHz	1.7	1.3	
			1 MHz	1.1	0.9	
			500 kHz	0.8	0.7	
			125 kHz	0.6	0.55	

1. Typical values are measures at T<sub>A</sub> = 25 °C, V<sub>DD</sub> = 3.3 V.
2. Add an additional power consumption of 0.8 mA for the ADC and of 0.5 mA for the DAC analog part. In applications, this consumption occurs only while the ADC is on (ADON bit is set in the ADC\_CR2 register).
3. An 8 MHz crystal is used as the external clock source. The AHB prescaler is used to reduce the frequency when f<sub>HCLK</sub> < 8 MHz, the PLL is used when f<sub>HCLK</sub> > 8 MHz.

Figure 14. Typical application with a 32.768 kHz crystal



### 5.3.7 Internal clock source characteristics

The parameters given in [Table 24](#) are derived from tests performed under the ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 9](#).

#### High-speed internal (HSI) RC oscillator

Table 24. HSI oscillator characteristics<sup>(1)</sup>

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{HSI}$	Frequency	-	-	8	-	MHz
$ACC_{HSI}$	Accuracy of HSI oscillator	$T_A = -40$ to $105\text{ }^{\circ}\text{C}^{(2)}$	-2.4	-	2.5	%
		$T_A = -10$ to $85\text{ }^{\circ}\text{C}^{(2)}$	-2.2	-	1.3	%
		$T_A = 0$ to $70\text{ }^{\circ}\text{C}^{(2)}$	-1.9	-	1.3	%
		$T_A = 25\text{ }^{\circ}\text{C}$	-1	-	1	%
$t_{su(HSI)}^{(3)}$	HSI oscillator startup time	-	1	-	2	$\mu\text{s}$
$I_{DD(HSI)}^{(3)}$	HSI oscillator power consumption	-	-	80	100	$\mu\text{A}$

1.  $V_{DD} = 3.3\text{ V}$ ,  $T_A = -40$  to  $105\text{ }^{\circ}\text{C}$  unless otherwise specified.

2. Based on characterization, not tested in production.

3. Guaranteed by design. Not tested in production

#### Low-speed internal (LSI) RC oscillator

Table 25. LSI oscillator characteristics<sup>(1)</sup>

Symbol	Parameter	Min	Typ	Max	Unit
$f_{LSI}$	Frequency	30	40	60	kHz
$t_{su(LSI)}^{(2)}$	LSI oscillator startup time	-	-	85	$\mu\text{s}$
$I_{DD(LSI)}^{(2)}$	LSI oscillator power consumption	-	0.65	1.2	$\mu\text{A}$

1.  $V_{DD} = 3\text{ V}$ ,  $T_A = -40$  to  $105\text{ }^{\circ}\text{C}$  unless otherwise specified.

2. Guaranteed by design, not tested in production.

Table 28. Flash memory characteristics

Symbol	Parameter	Conditions	Min <sup>(1)</sup>	Typ	Max <sup>(1)</sup>	Unit
$t_{\text{prog}}$	16-bit programming time	$T_A = -40$ to $+105$ °C	40	52.5	70	μs
$t_{\text{ERASE}}$	Page (2 KB) erase time	$T_A = -40$ to $+105$ °C	20	-	40	ms
$t_{\text{ME}}$	Mass erase time	$T_A = -40$ to $+105$ °C	20	-	40	ms
$I_{\text{DD}}$	Supply current	Read mode $f_{\text{HCLK}} = 24$ MHz, $V_{\text{DD}} = 3.3$ V	-	-	20	mA
		Write / Erase modes $f_{\text{HCLK}} = 24$ MHz, $V_{\text{DD}} = 3.3$ V	-	-	5	mA
		Power-down mode / Halt, $V_{\text{DD}} = 3.0$ to $3.6$ V	-	-	50	μA
$V_{\text{prog}}$	Programming voltage	-	2	-	3.6	V

1. Guaranteed by design, not tested in production.

Table 29. Flash memory endurance and data retention

Symbol	Parameter	Conditions	Value			Unit
			Min <sup>(1)</sup>	Typ	Max	
$N_{\text{END}}$	Endurance	$T_A = -40$ to $+85$ °C (6 suffix versions) $T_A = -40$ to $+105$ °C (7 suffix versions)	10	-	-	kcycles
$t_{\text{RET}}$	Data retention	1 kcycle <sup>(2)</sup> at $T_A = 85$ °C	30	-	-	Years
		1 kcycle <sup>(2)</sup> at $T_A = 105$ °C	10	-	-	
		10 kcycles <sup>(2)</sup> at $T_A = 55$ °C	20	-	-	

1. Based on characterization not tested in production.

2. Cycling performed over the whole temperature range.

### 5.3.10 FSMC characteristics

#### Asynchronous waveforms and timings

Figure 15 through Figure 18 represent asynchronous waveforms and Table 30 through Table 33 provide the corresponding timings. The results shown in these tables are obtained with the following FSMC configuration:

- AddressSetupTime = 0
- AddressHoldTime = 1
- DataSetupTime = 1

Table 34. Synchronous multiplexed NOR/PSRAM read timings<sup>(1)(2)</sup>

Symbol	Parameter	Min	Max	Unit
$t_{w(CLK)}$	FSMC_CLK period	27.7	-	ns
$t_{d(CLKL-NExL)}$	FSMC_CLK low to FSMC_NEx low (x = 0...2)	-	1.5	ns
$t_{d(CLKL-NExH)}$	FSMC_CLK low to FSMC_NEx high (x = 0...2)	2	-	ns
$t_{d(CLKL-NADV_L)}$	FSMC_CLK low to FSMC_NADV low	-	4	ns
$t_{d(CLKL-NADV_H)}$	FSMC_CLK low to FSMC_NADV high	5	-	ns
$t_{d(CLKL-AV)}$	FSMC_CLK low to FSMC_Ax valid (x = 16...25)	-	0	ns
$t_{d(CLKL-AIV)}$	FSMC_CLK low to FSMC_Ax invalid (x = 16...25)	2	-	ns
$t_{d(CLKH-NOEL)}$	FSMC_CLK high to FSMC_NOE low	-	1	ns
$t_{d(CLKL-NOEH)}$	FSMC_CLK low to FSMC_NOE high	0.5	-	ns
$t_{d(CLKL-ADV)}$	FSMC_CLK low to FSMC_AD[15:0] valid	-	12	ns
$t_{d(CLKL-ADIV)}$	FSMC_CLK low to FSMC_AD[15:0] invalid	0	-	ns
$t_{su(ADV-CLKH)}$	FSMC_A/D[15:0] valid data before FSMC_CLK high	6	-	ns
$t_h(CLKH-ADV)$	FSMC_A/D[15:0] valid data after FSMC_CLK high	0	-	ns
$t_{su(NWAITV-CLKH)}$	FSMC_NWAIT valid before FSMC_CLK high	8	-	ns
$t_h(CLKH-NWAITV)$	FSMC_NWAIT valid after FSMC_CLK high	2	-	ns

1.  $C_L = 15$  pF.

2. Preliminary values.

### Electromagnetic Interference (EMI)

The electromagnetic field emitted by the device is monitored while a simple application is executed (toggling 2 LEDs through the I/O ports). This emission test is compliant with IEC 61967-2 standard which specifies the test board and the pin loading.

**Table 39. EMI characteristics**

Symbol	Parameter	Conditions	Monitored frequency band	Max vs. [ $f_{HSE}/f_{HCLK}$ ]	Unit
				8/24 MHz	
$S_{EMI}$	Peak level	$V_{DD} = 3.6\text{ V}$ , $T_A = 25^\circ\text{C}$ , LQFP144 package compliant with SAE J1752/3	0.1 MHz to 30 MHz	16	dB $\mu$ V
			30 MHz to 130 MHz	25	
			130 MHz to 1GHz	25	
			SAE EMI Level	4	-

### 5.3.12 Absolute maximum ratings (electrical sensitivity)

Based on three different tests (ESD, LU) using specific measurement methods, the device is stressed in order to determine its performance in terms of electrical sensitivity.

#### Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts  $\times$  (n+1) supply pins). This test conforms to the JESD22-A114/C101 standard.

**Table 40. ESD absolute maximum ratings**

Symbol	Ratings	Conditions	Class	Maximum value <sup>(1)</sup>	Unit
$V_{ESD(HBM)}$	Electrostatic discharge voltage (human body model)	$T_A = +25^\circ\text{C}$ conforming to JESD22-A114	2	2000	V
$V_{ESD(CDM)}$	Electrostatic discharge voltage (charge device model)	$T_A = +25^\circ\text{C}$ conforming to JESD22-C101	II	500	

1. Based on characterization results, not tested in production.

#### Static latch-up

Two complementary static tests are required on six parts to assess the latch-up performance:

- A supply overvoltage is applied to each power supply pin
- A current injection is applied to each input, output and configurable I/O pin

These tests are compliant with EIA/JESD78 IC latch-up standard.

**Table 41. Electrical sensitivities**

Symbol	Parameter	Conditions	Class
LU	Static latch-up class	$T_A = +105^\circ\text{C}$ conforming to JESD78	II level A

### Output voltage levels

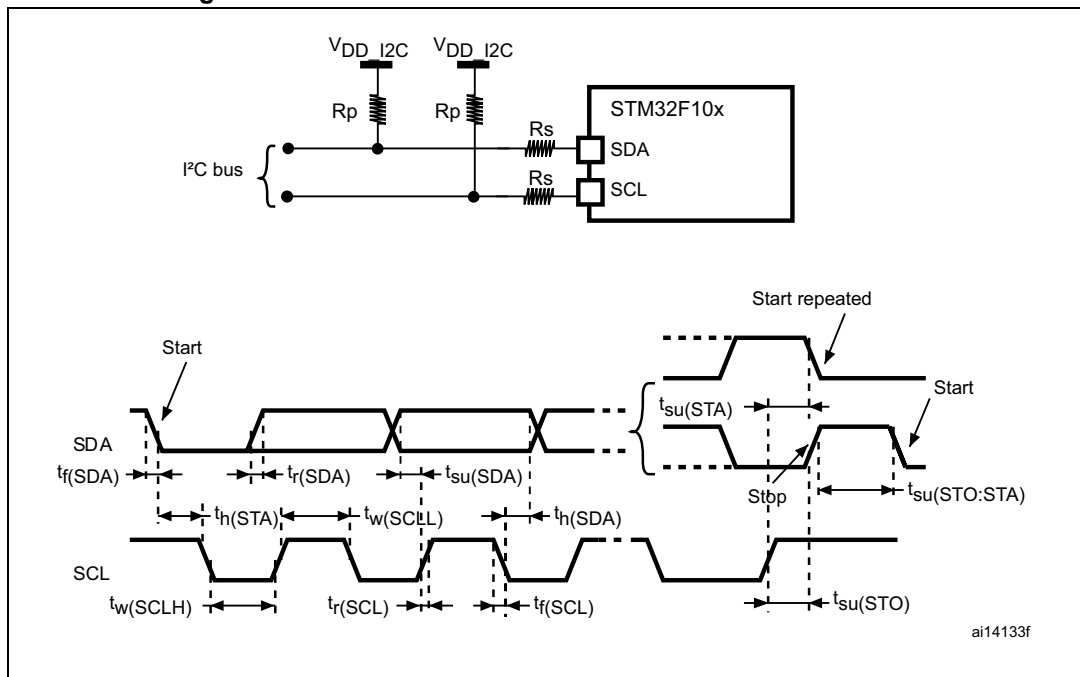
Unless otherwise specified, the parameters given in [Table 44](#) are derived from tests performed under the ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 9](#). All I/Os are CMOS and TTL compliant.

**Table 44. Output voltage characteristics**

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{OL}^{(1)}$	Output Low level voltage for an I/O pin when 8 pins are sunk at the same time	CMOS port <sup>(2)</sup> , $I_{IO} = +8 \text{ mA}$ , $2.7 \text{ V} < V_{DD} < 3.6 \text{ V}$	-	0.4	V
$V_{OH}^{(3)}$	Output High level voltage for an I/O pin when 8 pins are sourced at the same time		$V_{DD}-0.4$	-	
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin when 8 pins are sunk at the same time	TTL port <sup>(2)</sup> , $I_{IO} = +8 \text{ mA}$ , $2.7 \text{ V} < V_{DD} < 3.6 \text{ V}$	-	0.4	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin when 8 pins are sourced at the same time		2.4	-	
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin when 8 pins are sunk at the same time	$I_{IO} = +20 \text{ mA}^{(4)}$ , $2.7 \text{ V} < V_{DD} < 3.6 \text{ V}$	-	1.3	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin when 8 pins are sourced at the same time		$V_{DD}-1.3$	-	
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin when 8 pins are sunk at the same time	$I_{IO} = +6 \text{ mA}^{(4)}$ , $2 \text{ V} < V_{DD} < 2.7 \text{ V}$	-	0.4	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin when 8 pins are sourced at the same time		$V_{DD}-0.4$	-	

1. The  $I_{IO}$  current sunk by the device must always respect the absolute maximum rating specified in [Table 7](#) and the sum of  $I_{IO}$  (I/O ports and control pins) must not exceed  $I_{VSS}$ .
2. TTL and CMOS outputs are compatible with JEDEC standards JESD36 and JESD52.
3. The  $I_{IO}$  current sourced by the device must always respect the absolute maximum rating specified in [Table 7](#) and the sum of  $I_{IO}$  (I/O ports and control pins) must not exceed  $I_{VDD}$ .
4. Based on characterization data, not tested in production.



Figure 29. I<sup>2</sup>C bus AC waveforms and measurement circuit

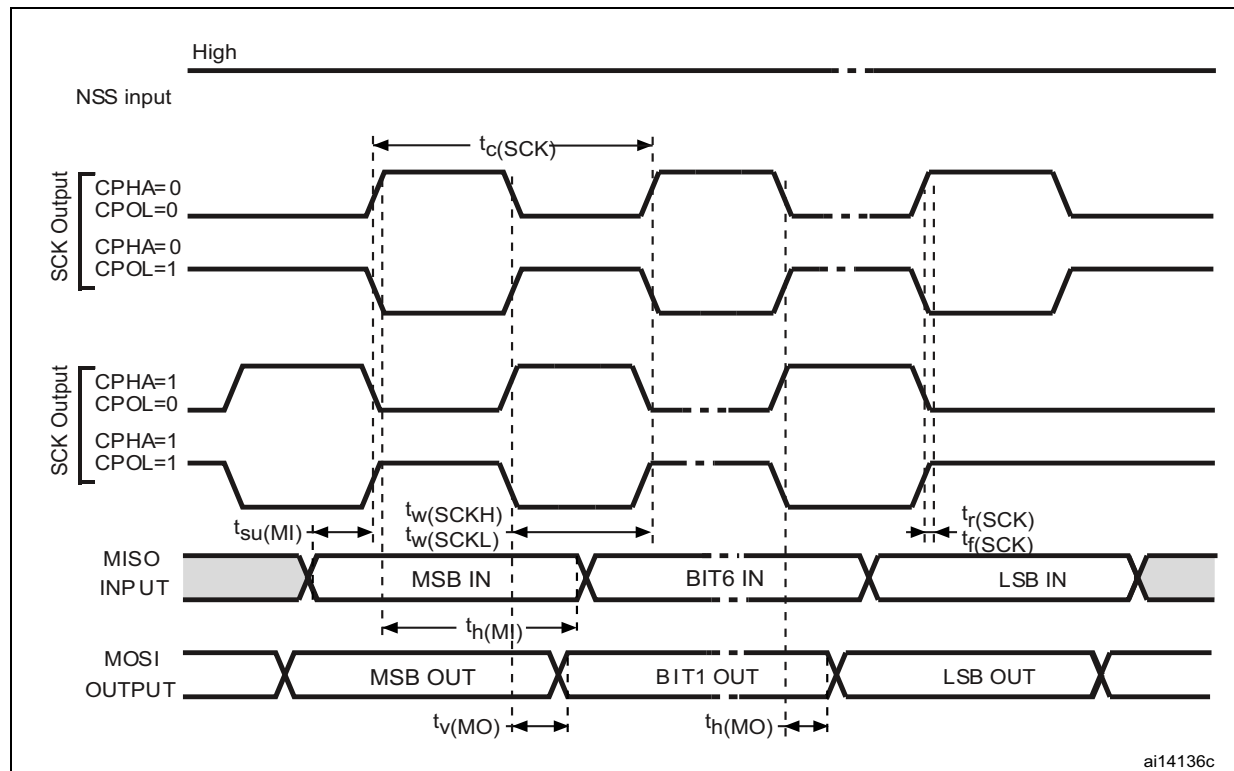
1. Measurement points are done at CMOS levels:  $0.3V_{DD}$  and  $0.7V_{DD}$ .

Table 49. SCL frequency ( $f_{PCLK1} = 24 \text{ MHz}$ ,  $V_{DD} = 3.3 \text{ V}$ )<sup>(1)(2)</sup>

$f_{SCL} \text{ (kHz)}^{(3)}$	I2C_CCR value
	$R_P = 4.7 \text{ k}\Omega$
400	0x8011
300	0x8016
200	0x8021
100	0x0064
50	0x00C8
20	0x01F4

- $R_P$  = External pull-up resistance,  $f_{SCL}$  = I<sup>2</sup>C speed,
- For speeds around 400 kHz, the tolerance on the achieved speed is of  $\pm 2\%$ . For other speed ranges, the tolerance on the achieved speed  $\pm 1\%$ . These variations depend on the accuracy of the external components used to design the application.
- Guaranteed by design, not tested in production.

Figure 32. SPI timing diagram - master mode



1. Measurement points are done at CMOS levels:  $0.3V_{DD}$  and  $0.7V_{DD}$ .

### HDMI consumer electronics control (CEC)

Refer to [Section 5.3.13: I/O current injection characteristics](#) for more details on the input/output alternate function characteristics.

### 5.3.18 12-bit ADC characteristics

Unless otherwise specified, the parameters given in [Table 51](#) are preliminary values derived from tests performed under the ambient temperature,  $f_{PCLK2}$  frequency and  $V_{DDA}$  supply voltage conditions summarized in [Table 9](#).

**Note:** *It is recommended to perform a calibration after each power-up.*

Table 52.  $R_{AIN}$  max for  $f_{ADC} = 12\text{ MHz}^{(1)}$ 

$T_s$ (cycles)	$t_s$ ( $\mu s$ )	$R_{AIN}$ max ( $k\Omega$ )
1.5	0.125	0.4
7.5	0.625	5.9
13.5	1.125	11.4
28.5	2.375	25.2
41.5	3.45	37.2
55.5	4.625	50
71.5	5.96	NA
239.5	20	NA

1. Guaranteed by design, not tested in production.

Table 53. ADC accuracy - limited test conditions<sup>(1)(2)</sup>

Symbol	Parameter	Test conditions	Typ	Max	Unit
ET	Total unadjusted error	$f_{PCLK2} = 24\text{ MHz}$ , $f_{ADC} = 12\text{ MHz}$ , $R_{AIN} < 10\text{ k}\Omega$ , $V_{DDA} = 3\text{ V to } 3.6\text{ V}$ , $V_{REF+} = V_{DDA}$ , $T_A = 25\text{ }^\circ\text{C}$ Measurements made after ADC calibration	$\pm 1.5$	$\pm 2.5$	LSB
EO	Offset error		$\pm 1$	$\pm 2$	
EG	Gain error		$\pm 0.5$	$\pm 1.5$	
ED	Differential linearity error		$\pm 1.5$	$\pm 2$	
EL	Integral linearity error		$\pm 1.5$	$\pm 2$	

1. ADC DC accuracy values are measured after internal calibration.

2. Preliminary values.

Table 54. ADC accuracy<sup>(1) (2) (3)</sup>

Symbol	Parameter	Test conditions	Typ	Max	Unit
ET	Total unadjusted error	$f_{PCLK2} = 24\text{ MHz}$ , $f_{ADC} = 12\text{ MHz}$ , $R_{AIN} < 10\text{ k}\Omega$ , $V_{DDA} = 2.4\text{ V to } 3.6\text{ V}$ , $T_A = \text{Full operating range}$ Measurements made after ADC calibration	$\pm 2$	$\pm 5$	LSB
EO	Offset error		$\pm 1.5$	$\pm 2.5$	
EG	Gain error		$\pm 1.5$	$\pm 3$	
ED	Differential linearity error		$\pm 1.5$	$\pm 2.5$	
EL	Integral linearity error		$\pm 1.5$	$\pm 4.5$	

1. ADC DC accuracy values are measured after internal calibration.

2. Better performance could be achieved in restricted  $V_{DD}$ , frequency,  $V_{REF}$  and temperature ranges.

3. Preliminary values.

**Note:** *ADC accuracy vs. negative injection current: Injecting a negative current on any analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative currents.*

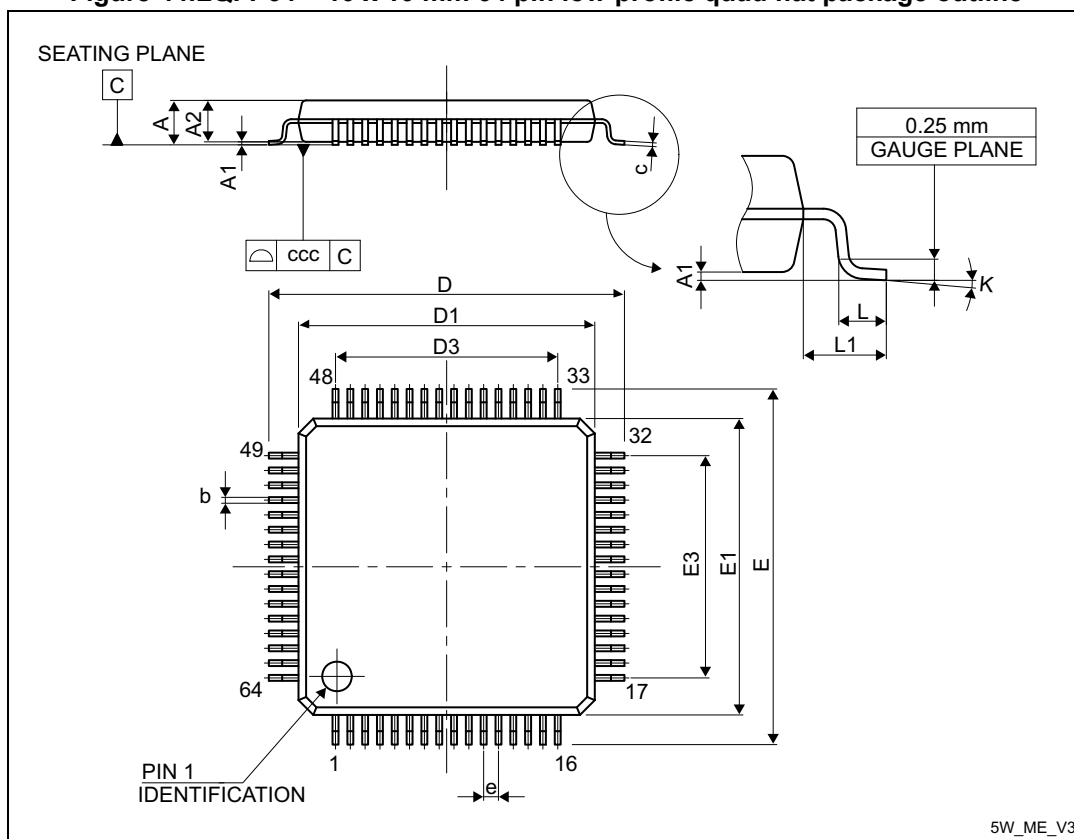
Table 57. LQFP144 - 144-pin, 20 x 20 mm low-profile quad flat package mechanical data

Symbol	millimeters			inches <sup>(1)</sup>		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	21.800	22.000	22.200	0.8583	0.8661	0.8740
D1	19.800	20.000	20.200	0.7795	0.7874	0.7953
D3	-	17.500	-	-	0.6890	-
E	21.800	22.000	22.200	0.8583	0.8661	0.8740
E1	19.800	20.000	20.200	0.7795	0.7874	0.7953
E3	-	17.500	-	-	0.6890	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

## 6.4 LQFP64 package information

Figure 44.LQFP64 – 10 x 10 mm 64 pin low-profile quad flat package outline



1. Drawing is not in scale.

Table 59. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package mechanical data

Symbol	millimeters			inches <sup>(1)</sup>		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	-	12.000	-	-	0.4724	-
D1	-	10.000	-	-	0.3937	-
D3	-	7.500	-	-	0.2953	-
E	-	12.000	-	-	0.4724	-
E1	-	10.000	-	-	0.3937	-
E3	-	7.500	-	-	0.2953	-